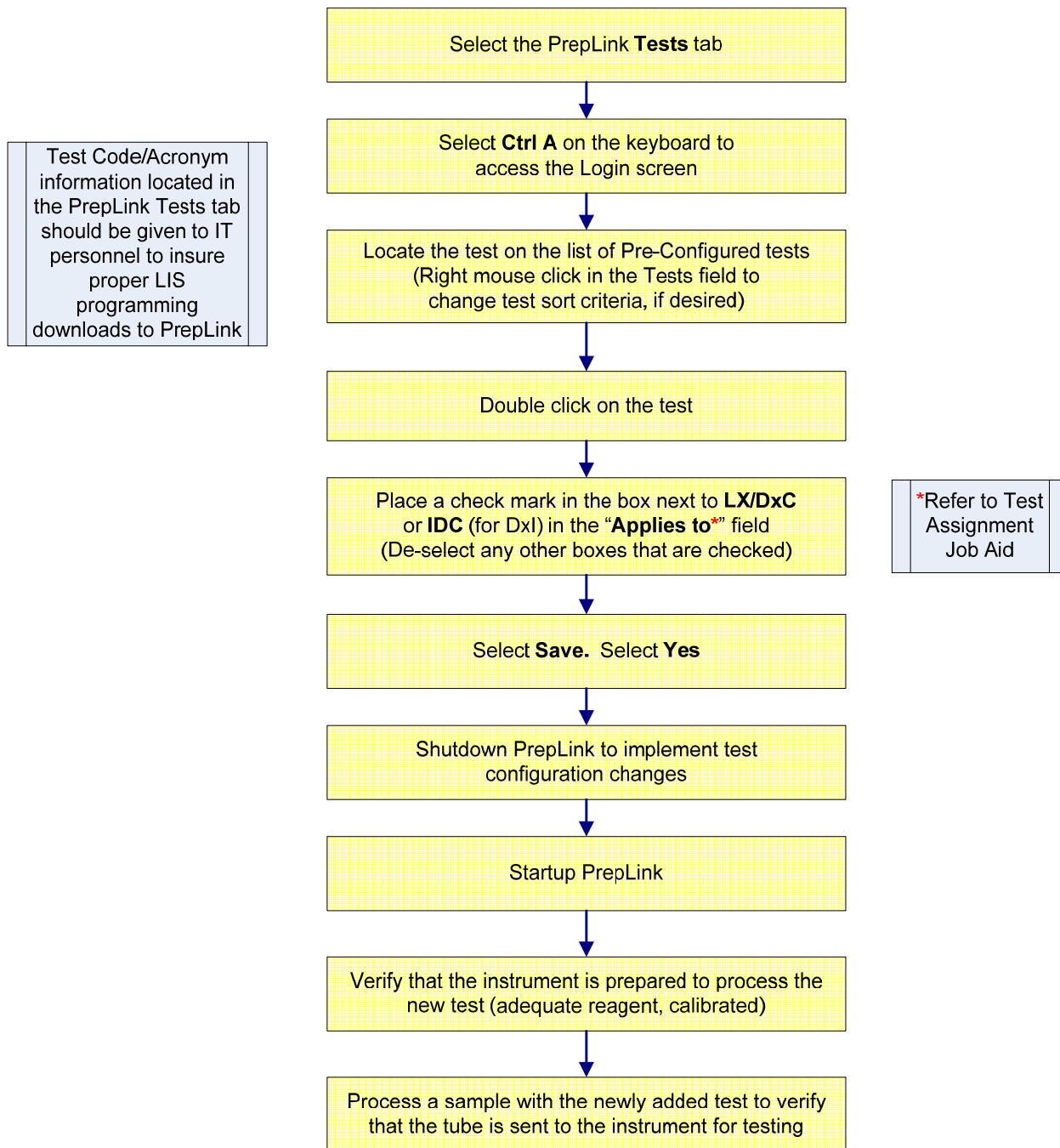


Power Processor: Configure a Test on a Connected Instrument LX/DxC or DxI

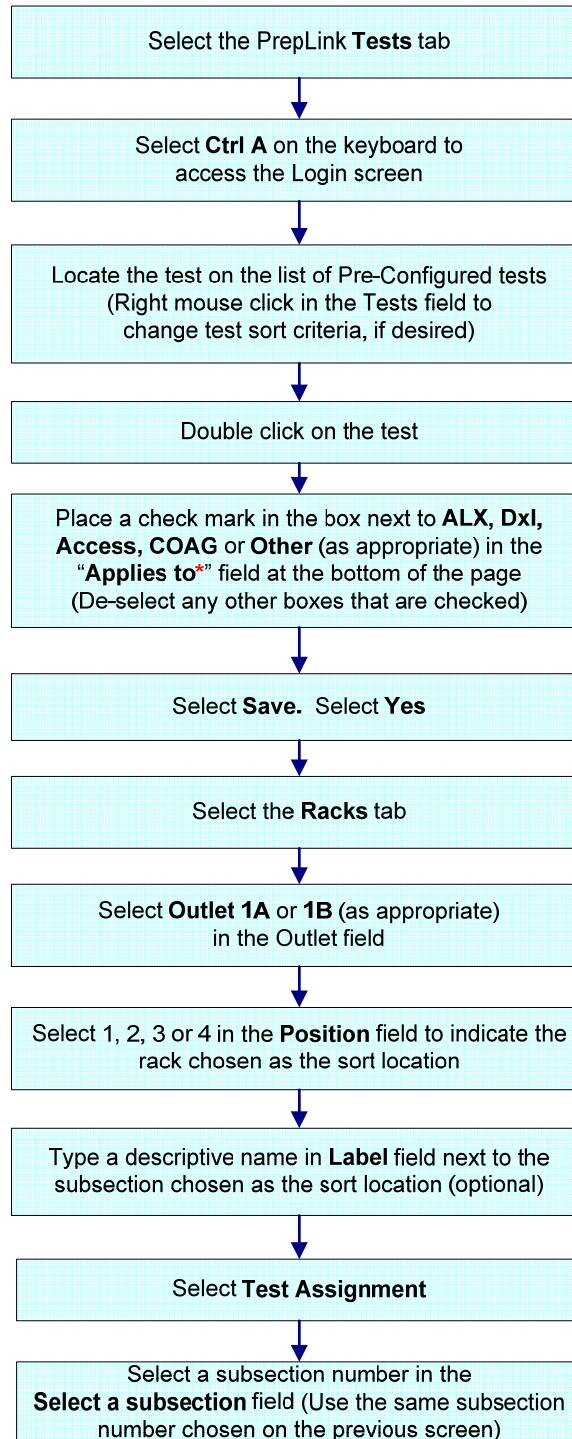
Test configurations for the LX/DxC, IDC, ALX, DxI, Access and GEN•S analyzers are stored in the PrepLink database. The operator must type test configuration information for analysis on instruments other than those listed.



Power Processor: Configure a Test to Sort to Outlet 1A or 1B

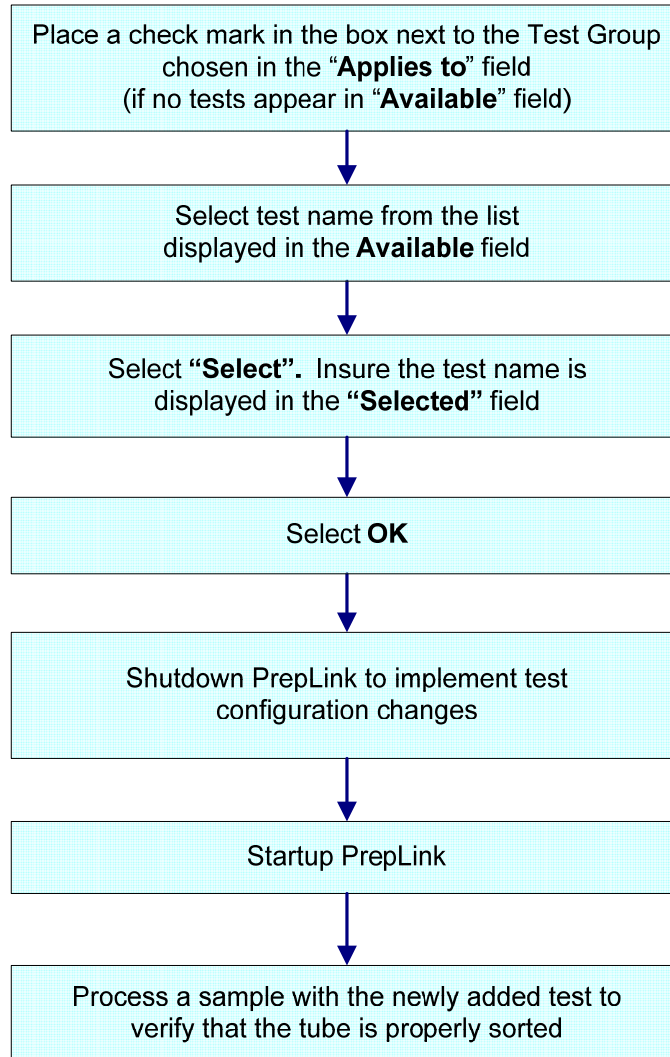
Test configurations for the LX/DxC, IDC, ALX, Dxl, Access and GEN-S analyzers are stored in the PrepLink database. The operator must type test configuration information for analysis on instruments other than those listed.

Test Code/Acronym information located in the PrepLink Tests tab should be given to IT personnel to insure proper LIS programming downloads to PrepLink



*Refer to Test Assignment Job Aid

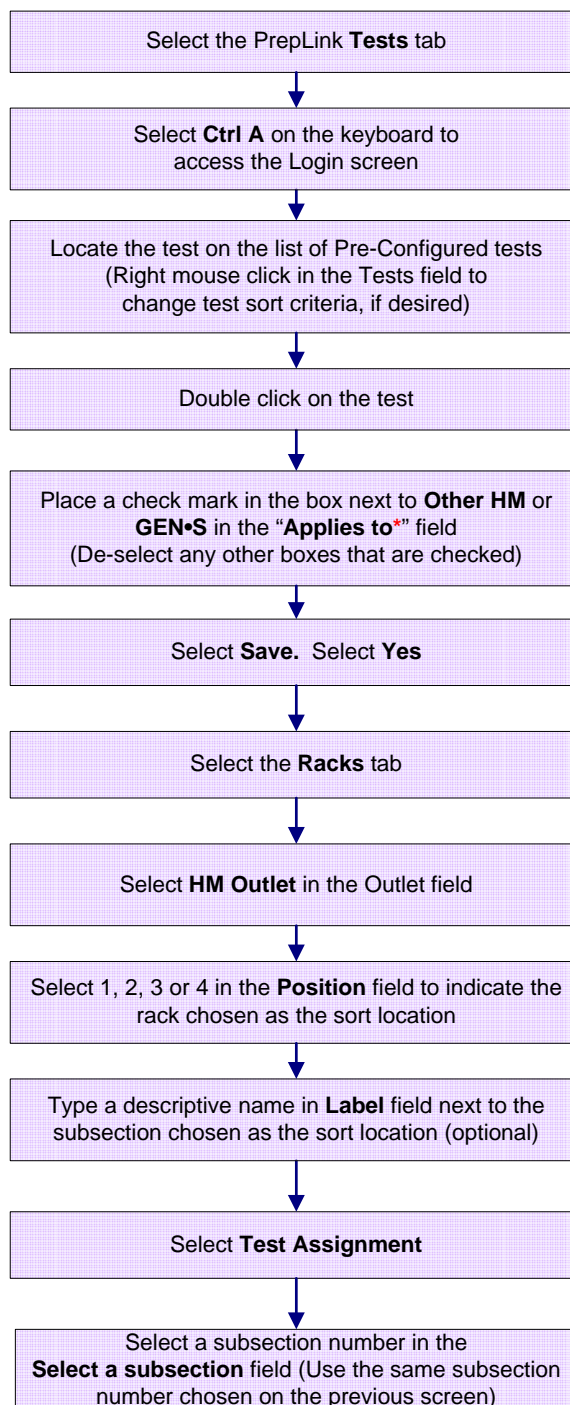
Power Processor:
Configure a Test to Sort to Outlet 1A or 1B,
Page Two



Power Processor: Configure a Test to Sort to HM Outlet

Test configurations for the LX/DxC, IDC, ALX, Dxl, Access and GEN•S analyzers are stored in the PrepLink database. The operator must type test configuration information for analysis on instruments other than those listed.

Test Code/Acronym information located in the PrepLink Tests tab should be given to IT personnel to insure proper LIS programming downloads to PrepLink



*Refer to Test Assignment Job Aid

Power Processor: Configure a Test to Sort to HM Outlet

